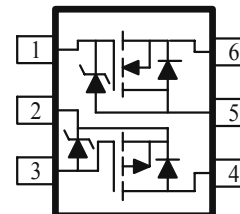
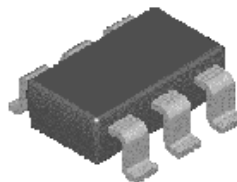


These miniature surface mount MOSFETs utilize High Cell Density process. Low  $r_{DS(on)}$  assures minimal power loss and conserves energy, making this device ideal for use in power management circuitry. Typical applications are DC-DC converters, power management in portable and battery-powered products such as computers, printers, PCMCIA cards, cellular and cordless telephones.

- Low  $r_{DS(on)}$  Provides Higher Efficiency and Extends Battery Life
- Miniature TSOP-6 Surface Mount Package Saves Board Space



$V_{DS}$ (V)	$r_{DS(on)}$ ( $\Omega$ )	$I_D$ (A)
25	0.45 @ $V_{GS} = 4.5V$	1.2
	0.72 @ $V_{GS} = 2.5V$	1.0
-25	1.09 @ $V_{GS} = -4.5V$	-0.85
	1.50 @ $V_{GS} = -2.5V$	-0.75

ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ C$ UNLESS OTHERWISE NOTED)					
Parameter	Symbol	N-Channel	P-Channel	Units	
Drain-Source Voltage	$V_{DS}$	25	-25	V	
Gate-Source Voltage	$V_{GS}$	8	-8		
Continuous Drain Current <sup>a</sup>	$I_D$	$T_A=25^\circ C$	1.2	-0.9	A
		$T_A=70^\circ C$	0.95	-0.65	
Pulsed Drain Current <sup>b</sup>	$I_{DM}$	$\pm 3.5$	$\pm 2.5$		
Continuous Source Current (Diode Conduction) <sup>a</sup>	$I_S$	1	-1	A	
Power Dissipation <sup>a</sup>	$P_D$	$T_A=25^\circ C$	1.25		W
		$T_A=70^\circ C$	0.8		
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$			-55 to 150	$^\circ C$

THERMAL RESISTANCE RATINGS				
Parameter	Symbol	Maximum	Units	
Maximum Junction-to-Ambient <sup>a</sup>	$t \leq 5 \text{ sec}$	$R_{THJA}$	100	$^\circ C/W$

Notes

- Surface Mounted on 1" x 1" FR4 Board.
- Pulse width limited by maximum junction temperature



SPECIFICATIONS (T <sub>A</sub> = 25°C UNLESS OTHERWISE NOTED)							
Parameter	Symbol	Test Conditions	Limits				Unit
			Ch	Min	Typ	Max	
<b>Static</b>							
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	N	25			V
		V <sub>GS</sub> = 0 V, I <sub>D</sub> = -250 μA	P	-25			
Gate-Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250 μA	N	0.65	0.81	1.5	V
		V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = -250 μA	P	-0.65	-0.83	-1.5	
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 8 V	N			100	μA
		V <sub>DS</sub> = 0 V, V <sub>GS</sub> = -8 V	P			-100	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V	N			1	μA
		V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55°C				10	
On-State Drain Current <sup>A</sup>	I <sub>D(on)</sub>	V <sub>DS</sub> = 5 V, V <sub>GS</sub> = 4.5 V	N	1			A
		V <sub>DS</sub> = -5 V, V <sub>GS</sub> = -4.5 V	P	-1			
Drain-Source On-Resistance <sup>A</sup>	r <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 0.5 A	N		0.35	0.45	Ω
		V <sub>GS</sub> = 2.5 V, I <sub>D</sub> = 0.2 A			0.45	0.72	
		V <sub>GS</sub> = -4.5 V, I <sub>D</sub> = -0.41 A	P		0.860	1.09	
		V <sub>GS</sub> = -2.5 V, I <sub>D</sub> = -0.2 A			1.15	1.50	
Forward Transconductance <sup>A</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 0.5 A	N		1.45		S
		V <sub>DS</sub> = -5 V, I <sub>D</sub> = 0.4 A	P		0.9		
<b>Dynamic<sup>b</sup></b>							
Total Gate Charge	Q <sub>g</sub>	N-Channel V <sub>DS</sub> =5V, V <sub>GS</sub> =4.5V, I <sub>D</sub> =0.5A P-Channel V <sub>DS</sub> =-5V, V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-0.25A	N		1.64	2.3	nC
			P		1.1	1.5	
Gate-Source Charge	Q <sub>gs</sub>		N		0.4		
			P		0.33		
Gate-Drain Charge	Q <sub>gd</sub>		N		0.45		
			P		0.26		
<b>Switching</b>							
Turn-On Delay Time	t <sub>d(on)</sub>	N-Chaneel V <sub>DD</sub> =6V, V <sub>GS</sub> =4.5V, I <sub>D</sub> =0.5A , R <sub>GEN</sub> =50Ω, P-Channel V <sub>DD</sub> =-6V, V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-0.41A R <sub>GEN</sub> =50Ω	N		3	6	nS
			P		7	21	
Rise Time	t <sub>r</sub>		N		8.5	18	
			P		9	19	
Turn-Off Delay Time	t <sub>d(off)</sub>		N		17	30	
			P		55	112	
Fall-Time	t <sub>f</sub>		N		13	25	
			P		35	71	

Notes

- a. Pulse test: PW ≤ 300us duty cycle ≤ 2%.
- b. Guaranteed by design, not subject to production testing.